SCAS553A - NOVEMBER 1995 - REVISED MAY 1996

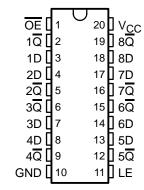
- Inputs Are TTL-Voltage Compatible
- 3-State Inverting Outputs Drive Bus Lines Directly
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

#### description

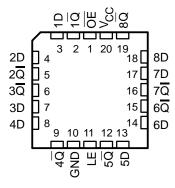
The 'ACT533 are octal transparent D-type latches with 3-state outputs. When the latch-enable (LE) input is high, the  $\overline{Q}$  outputs follow the complements of the data (D) inputs. When LE is taken low, the  $\overline{Q}$  outputs are latched at the inverted levels set up at the D inputs.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54ACT533 . . . J OR W PACKAGE SN74ACT533 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ACT533 . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT533 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ACT533 is characterized for operation from –40°C to 85°C.

### FUNCTION TABLE (each latch)

	INPUTS		OUTPUT
ŌĒ	LE	D	Q
L	Н	Н	L
L	Н	L	Н
L	L	Χ	$\overline{Q}_0$
Н	X	Χ	Z



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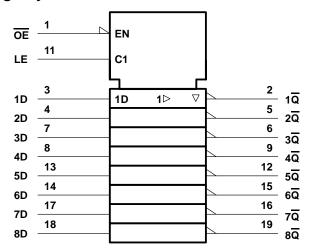
EPIC is a trademark of Texas Instruments Incorporated.



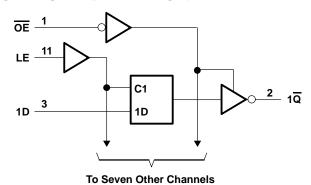
### SN54ACT533, SN74ACT533 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

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### logic symbol†



### logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )		±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )		±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$		±50 mA
Continuous current through V <sub>CC</sub> or GND		±200 mA
Maximum power dissipation at $T_A = 55^{\circ}$ C (in still air) (see Note 2)	): DB package	0.6 W
	DW package	1.6 W
	N package	1.3 W
	PW package	0.7 W
Storage temperature range, T <sub>stq</sub>		–65°C to 150°C

<sup>\$\</sup>frac{1}{2}\$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.



<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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### recommended operating conditions (see Note 3)

		SN54ACT533 SN74		SN74A	SN74ACT533		
		MIN	MAX	MIN	MAX	UNIT	
VCC	Supply voltage	4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage	2	7	2		V	
V <sub>IL</sub>	Low-level input voltage		0.8		0.8	V	
VI	Input voltage	0	Vcc	0	VCC	V	
۷o	Output voltage	0 /	Vcc	0	VCC	V	
loh	High-level output current	2	-24		-24	mA	
loL	Low-level output current	70	24		24	mA	
Δt/Δν	Input transition rise or fall rate	0	8	0	8	ns/V	
TA	Operating free-air temperature	<del>-</del> 55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST COMPITIONS	, , , , , , , , , , , , , , , , , , ,	T <sub>A</sub> = 25°C			SN54ACT533		SN74ACT533			
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
	In	4.5 V	4.4	4.49		4.4		4.4			
	I <sub>OH</sub> = -50 μA	5.5 V	5.4	5.49		5.4		5.4			
V	Jan - 24 mA	4.5 V	3.86			3.7		3.76		V	
VOH	$I_{OH} = -24 \text{ mA}$	5.5 V	4.86			4.7		4.76		V	
	I <sub>OH</sub> = -50 mA <sup>†</sup>	5.5 V				3.85					
	I <sub>OH</sub> = -75 mA <sup>†</sup>	5.5 V					12	3.85			
	Ι <sub>ΟL</sub> = 50 μΑ	4.5 V			0.1		0.1		0.1	٧	
		5.5 V			0.1		0.1		0.1		
\/a	I <sub>OL</sub> = 24 mA	4.5 V			0.36	Ė	0.5		0.44		
VOL		5.5 V			0.36	25	0.5		0.44		
	I <sub>OL</sub> = 50 mA <sup>†</sup>	5.5 V				20	1.65				
	I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V				Q'			1.65		
l <sub>OZ</sub>	$V_O = V_{CC}$ or GND	5.5 V			±0.25		±5		±2.5	μΑ	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ	
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μА	
∆l <sub>CC</sub> ‡	One input at 3.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V			0.6		1.6		1.5	mA	
C <sub>i</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5						pF	

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

<sup>‡</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

### SN54ACT533, SN74ACT533 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

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# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		TA = 25°C SN54ACT533 SN74ACT		CT533	UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, LE high	5		7.5	FIN	6		ns
t <sub>su</sub>	Setup time, data before LE↓	3		5.5	EL.	4		ns
th	Hold time, data after LE↓	2		40	7	2.5		ns

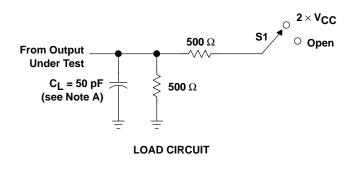
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ом то		25°C	SN54A	CT533	SN74A	CT533	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
<sup>t</sup> PLH	D	ρl	2.5	10.5	1.5	13	2	11.5	ns	
<sup>t</sup> PHL	Б	Q [	2.5	10	1.5	12.5	2	11	115	
<sup>t</sup> PLH	LE	ρl	2.5	10.5	1.5	13	2	11.5	ns	
<sup>t</sup> PHL	LL	l Q	2.5	10.5	1.5	13	2	11.5	115	
<sup>t</sup> PZH	<u>OE</u>	ρl	2	10	30	12.5	1.5	11	ns	
tPZL	UE	g	2	10	Q <sub>C</sub>	12.5	1.5	11	115	
<sup>t</sup> PHZ	ŌĒ	ΘI	2	10	2 1	12.5	1.5	11	ns	
t <sub>PLZ</sub>	OE .	Q	) <sup>E</sup>   Q	2	10	1	12.5	1.5	11	115

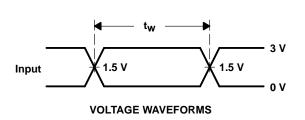
### operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

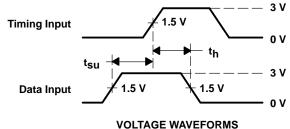
PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	40	pF

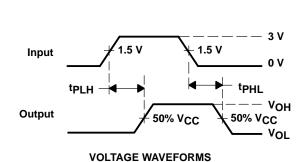
#### PARAMETER MEASUREMENT INFORMATION

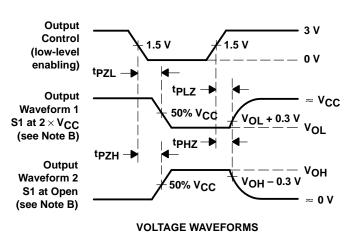


TEST	S1
tPLH/tPHL	Open
tPLZ/tPZL	2×V <sub>CC</sub>
tPHZ/tPZH	Open









NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 2.5$  ns,  $t_f \leq 2.5$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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